

FIG. 1

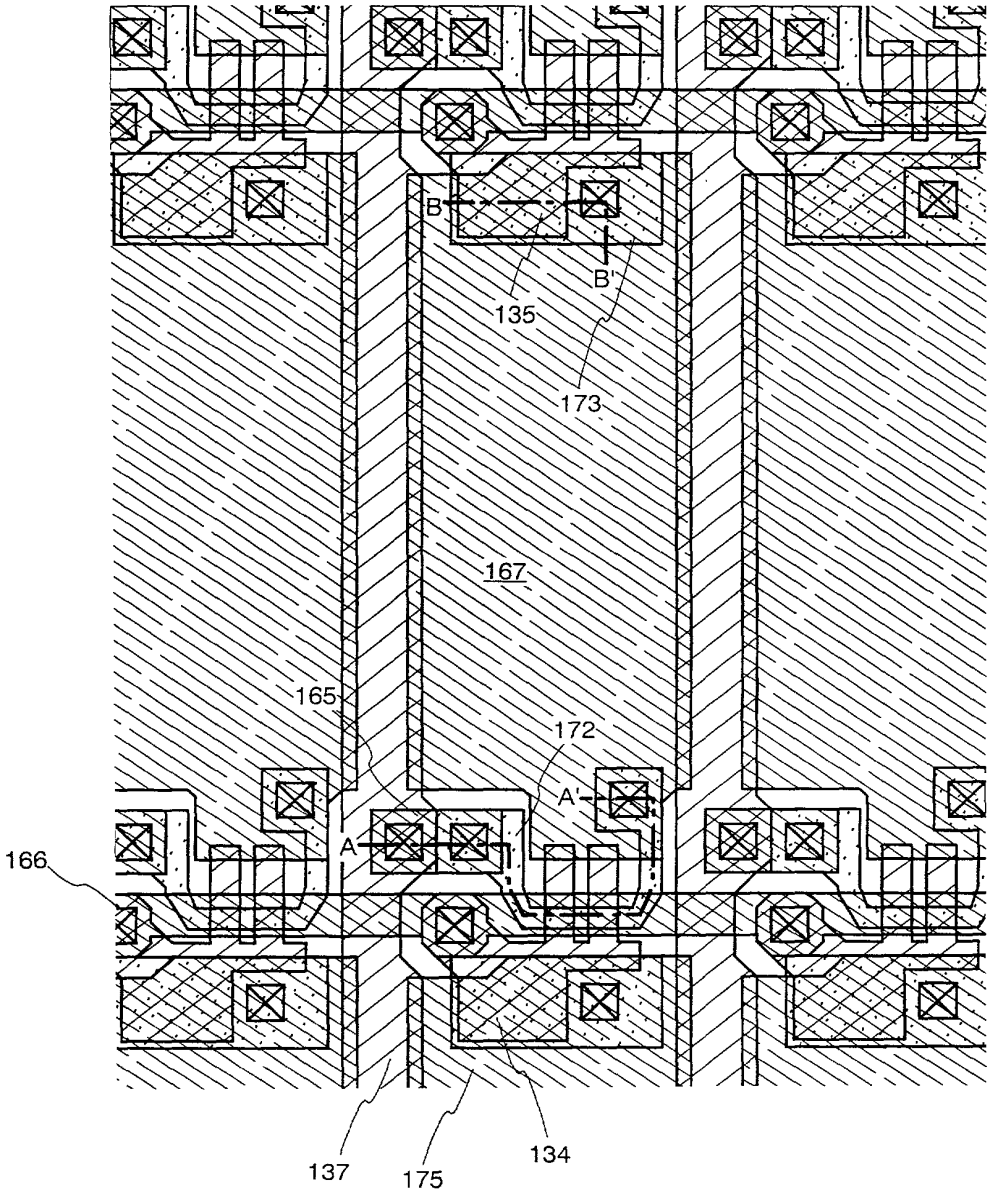


FIG. 2A

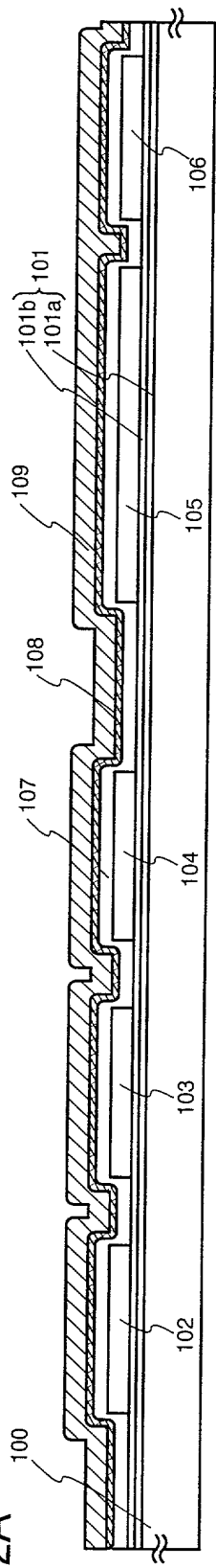


FIG. 2B n-type impurity

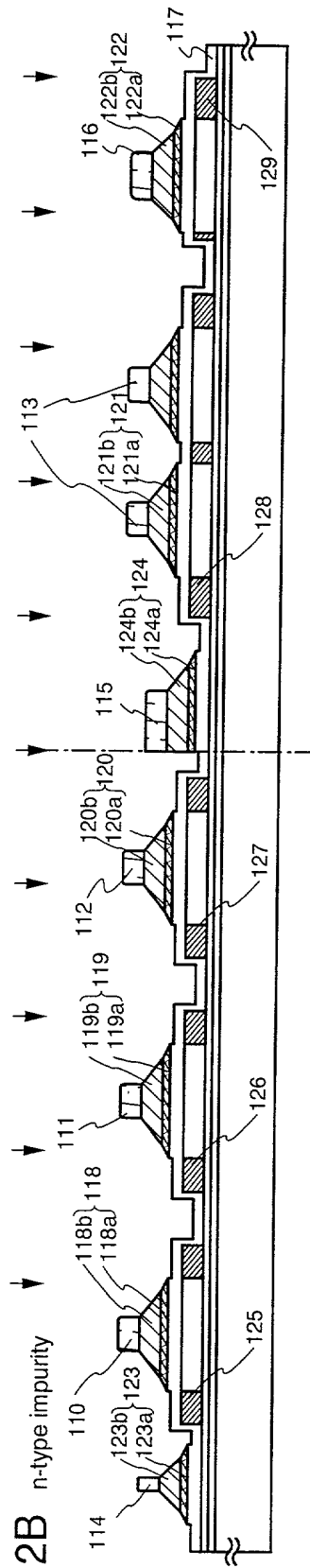
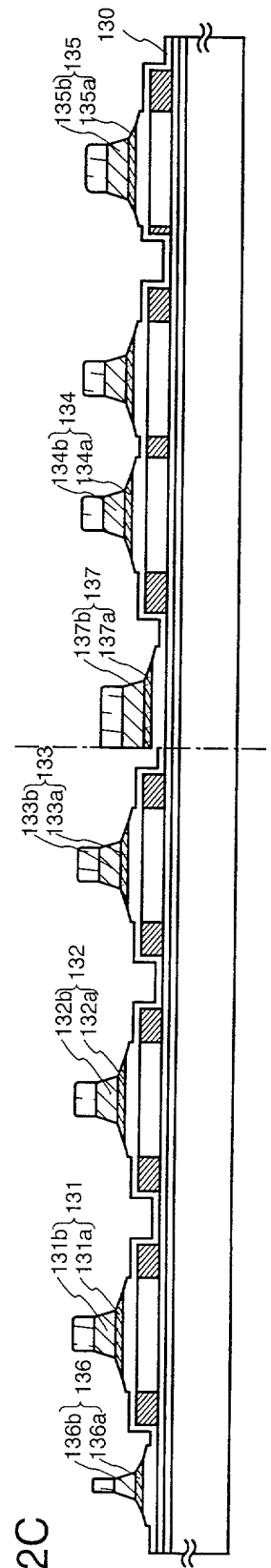
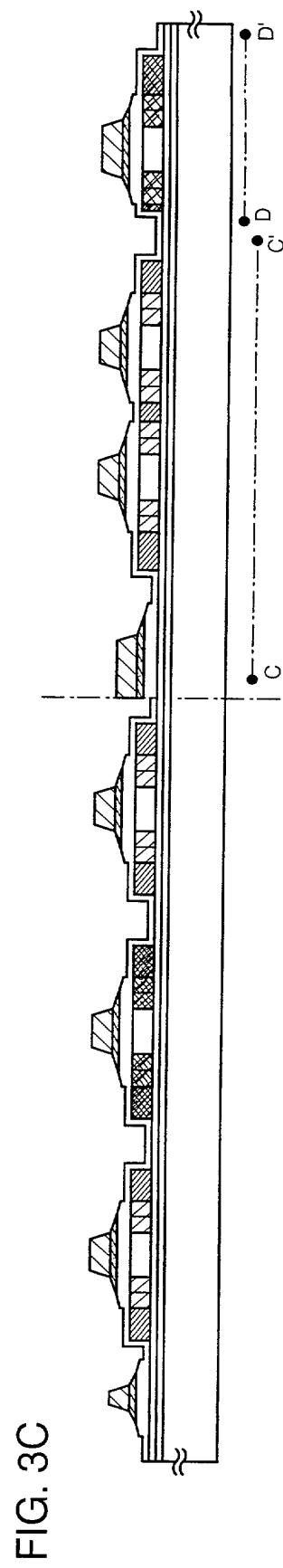
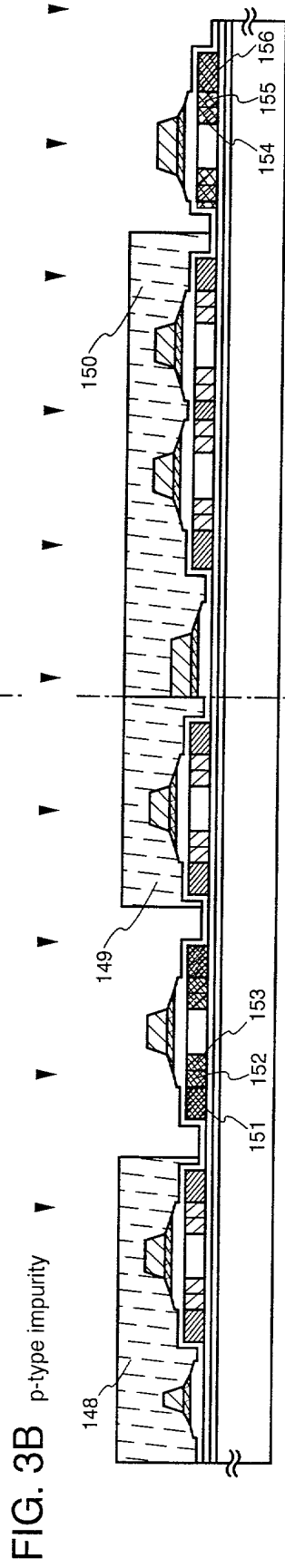
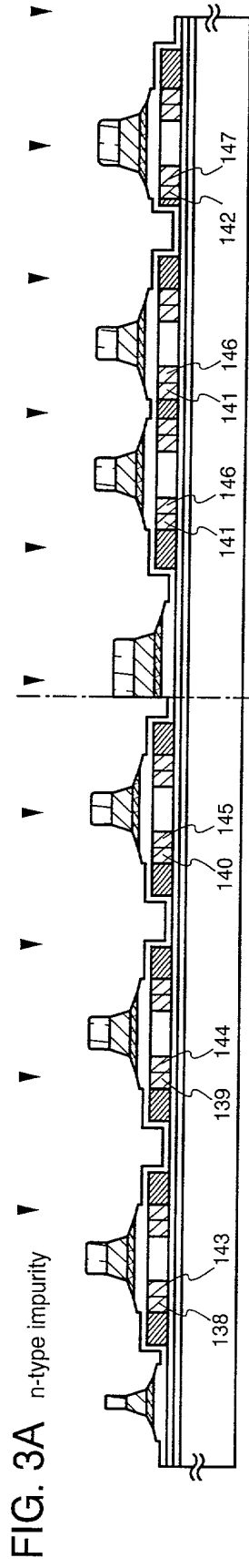


FIG. 2C





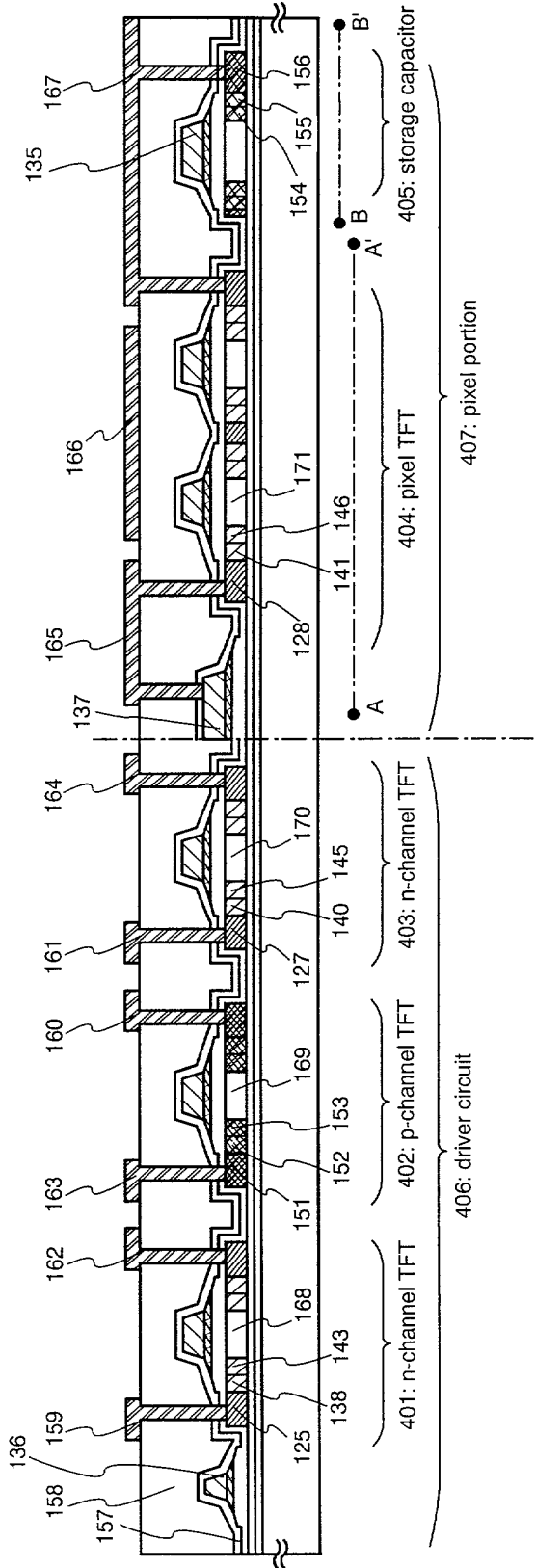


FIG. 4

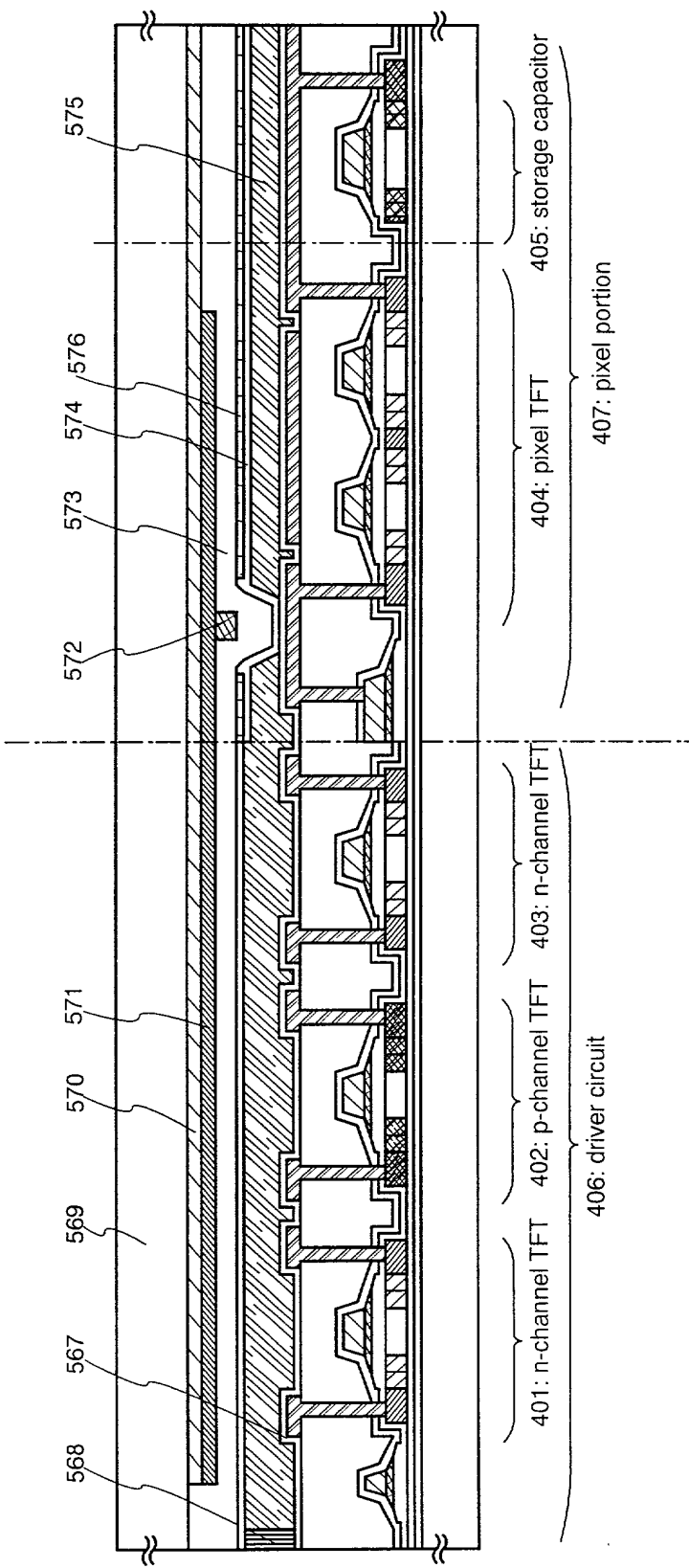
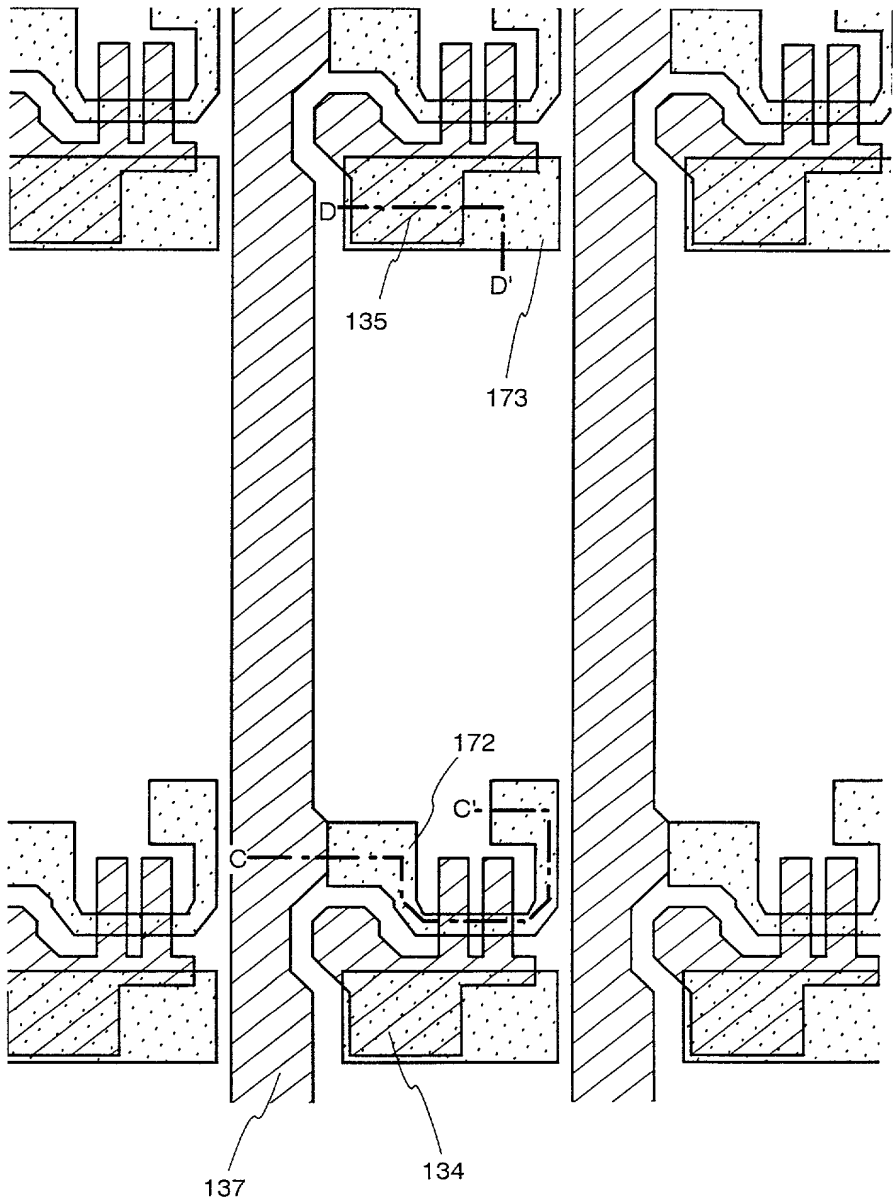


FIG. 5

FIG. 6



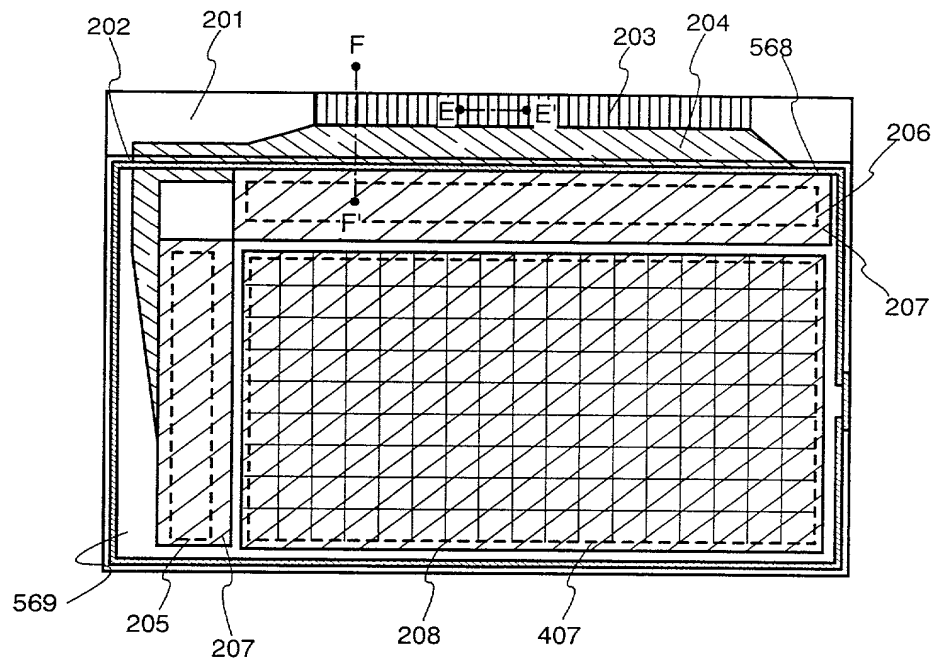


FIG. 7A top view

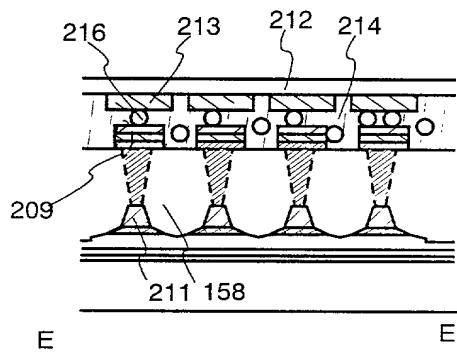


FIG. 7B cross sectional view of E-E'

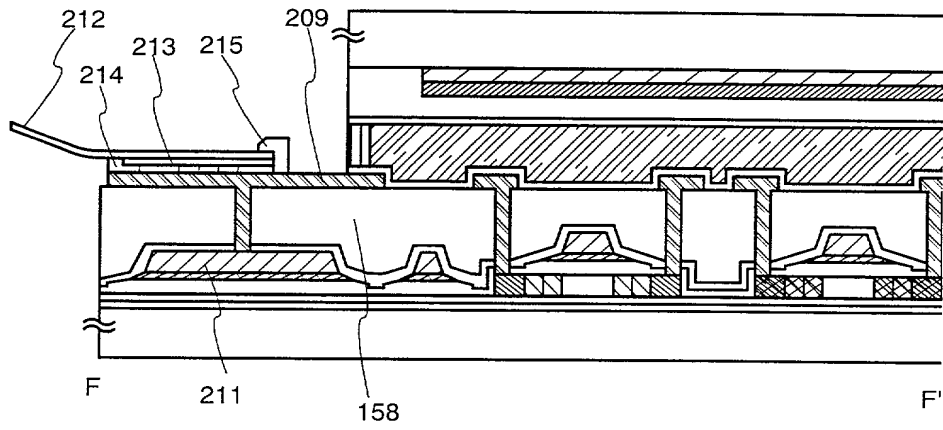


FIG. 8A cross sectional view of F-F'

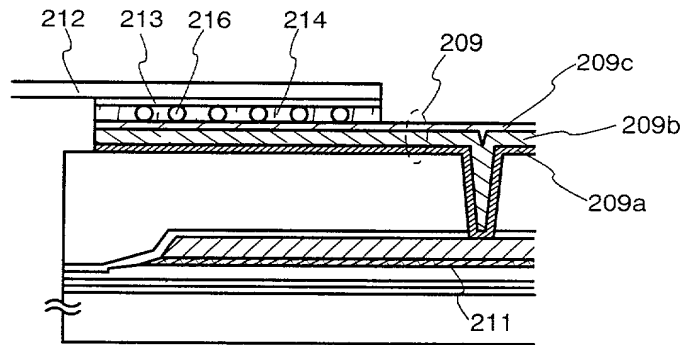


FIG. 8B



FIG. 9A

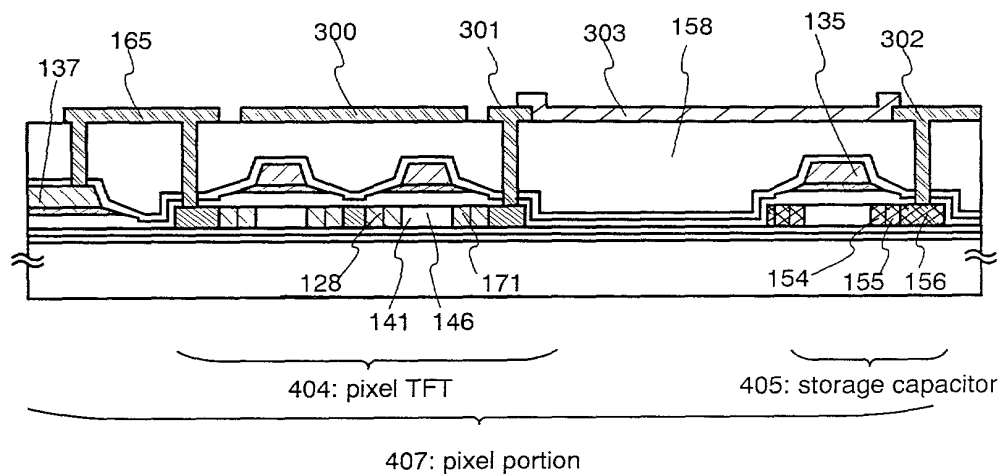


FIG. 9B

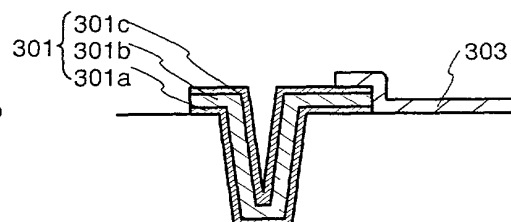


FIG. 9C

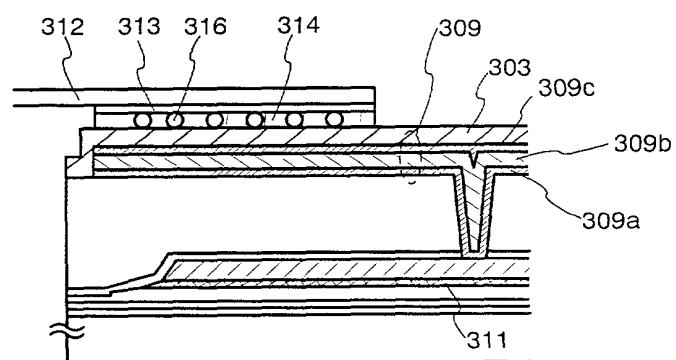


FIG. 10

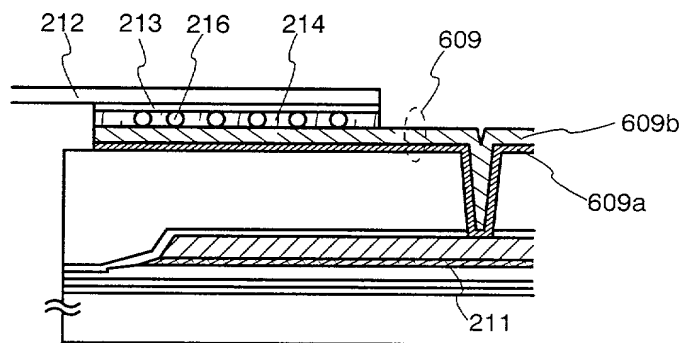


FIG. 11

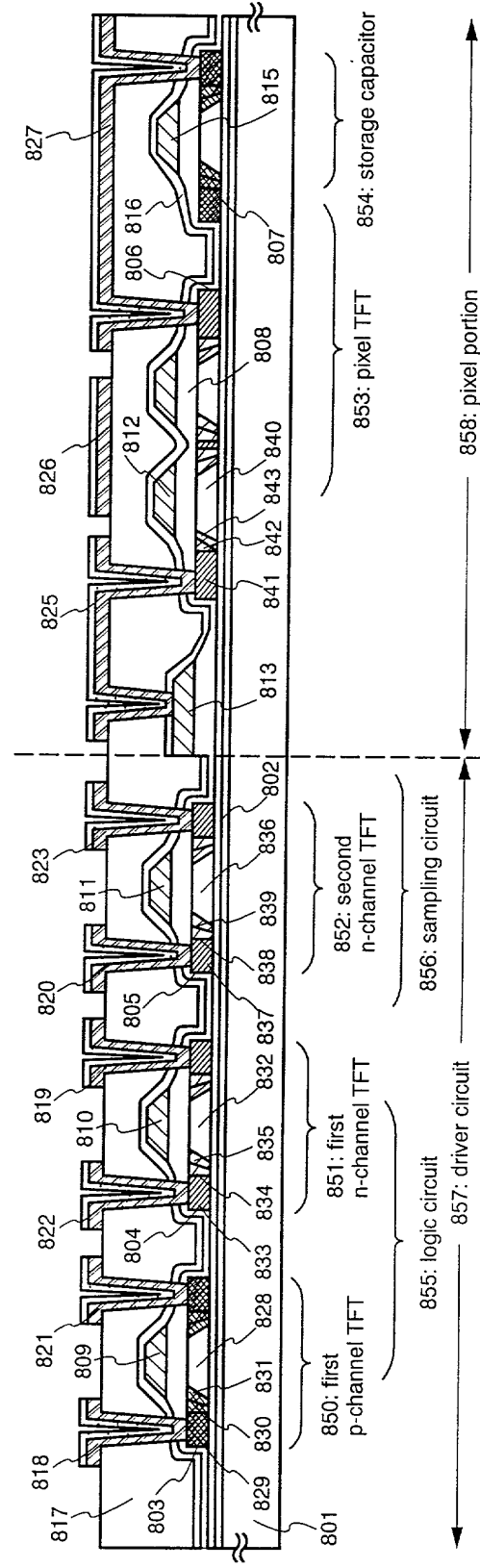


FIG. 12

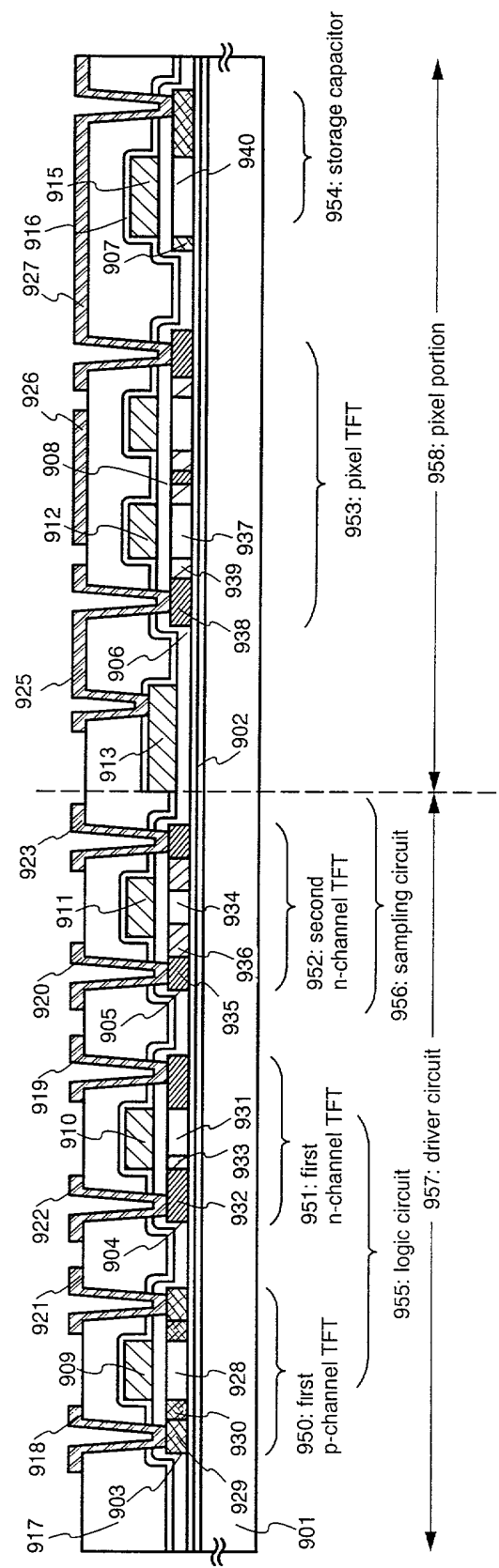


FIG. 13

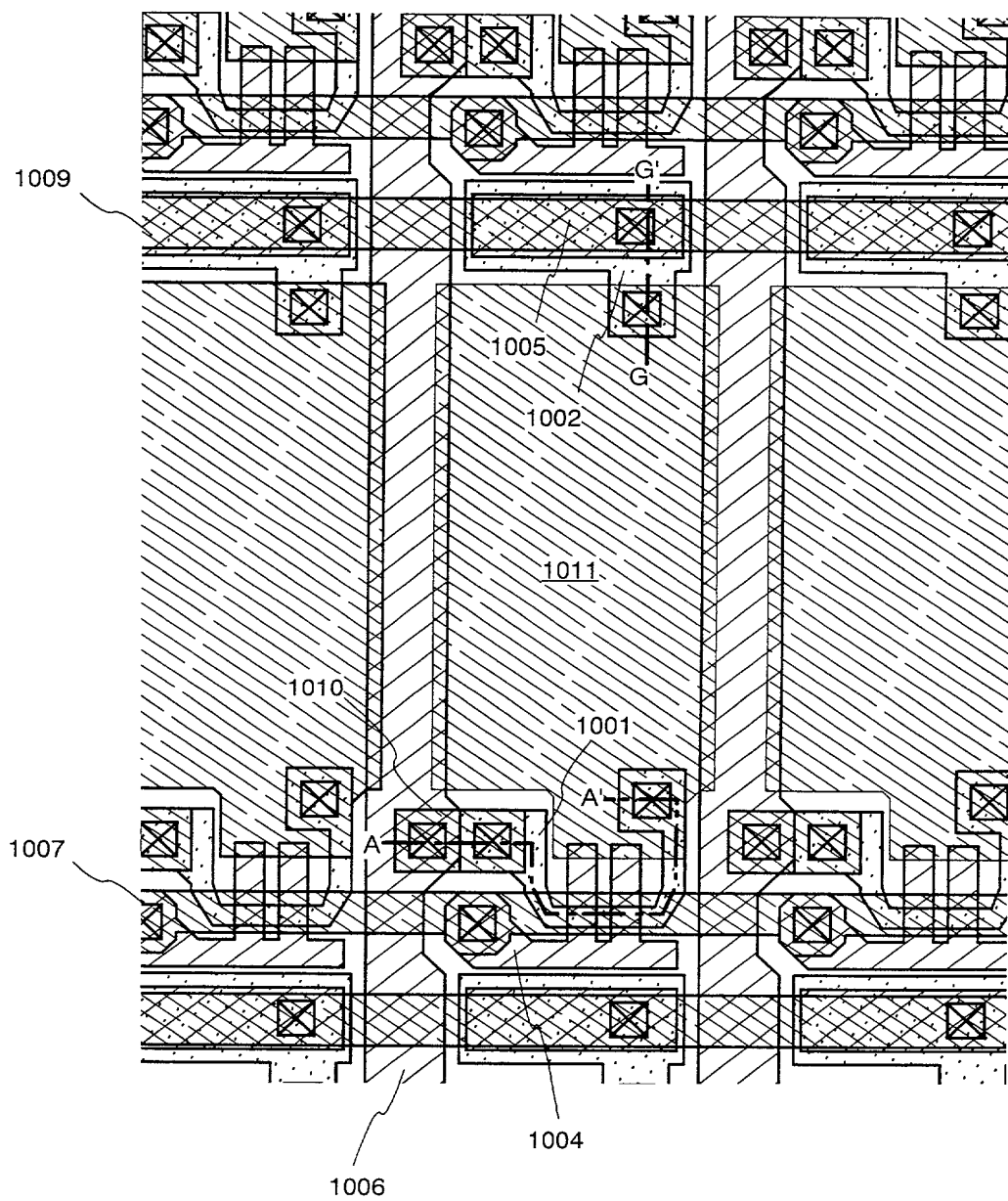


FIG. 14

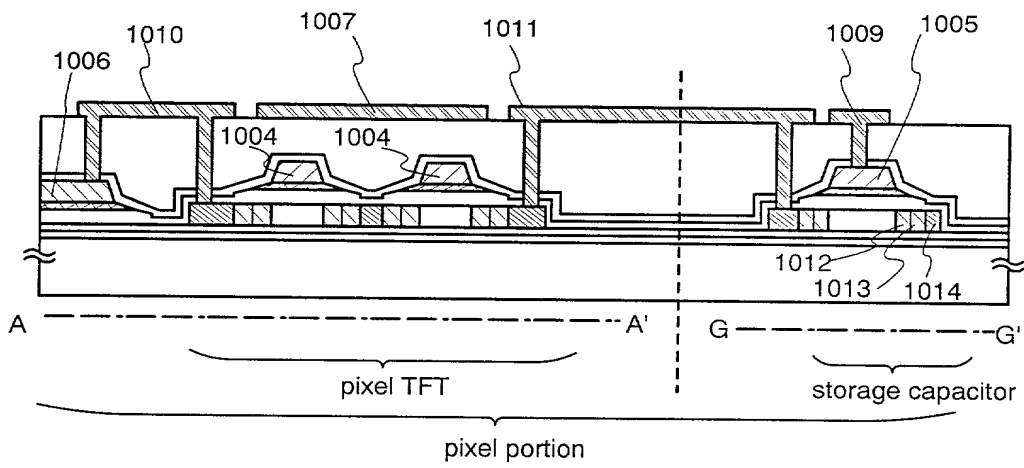


FIG. 15

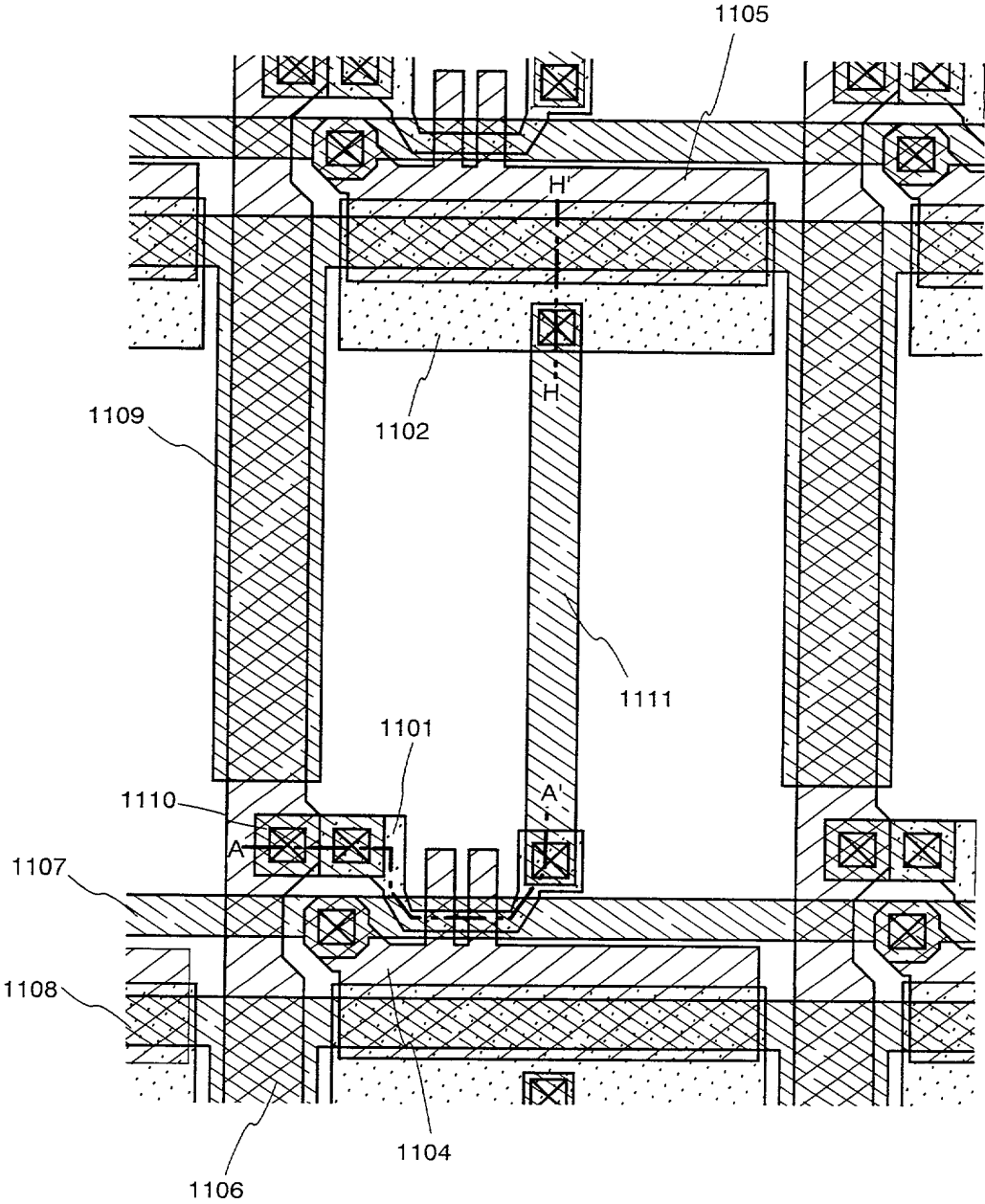


FIG. 16

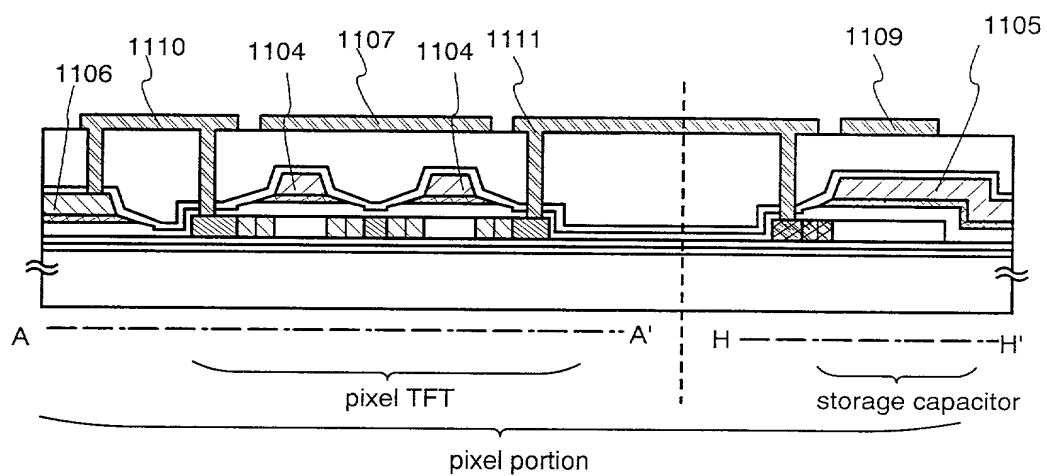




FIG. 17

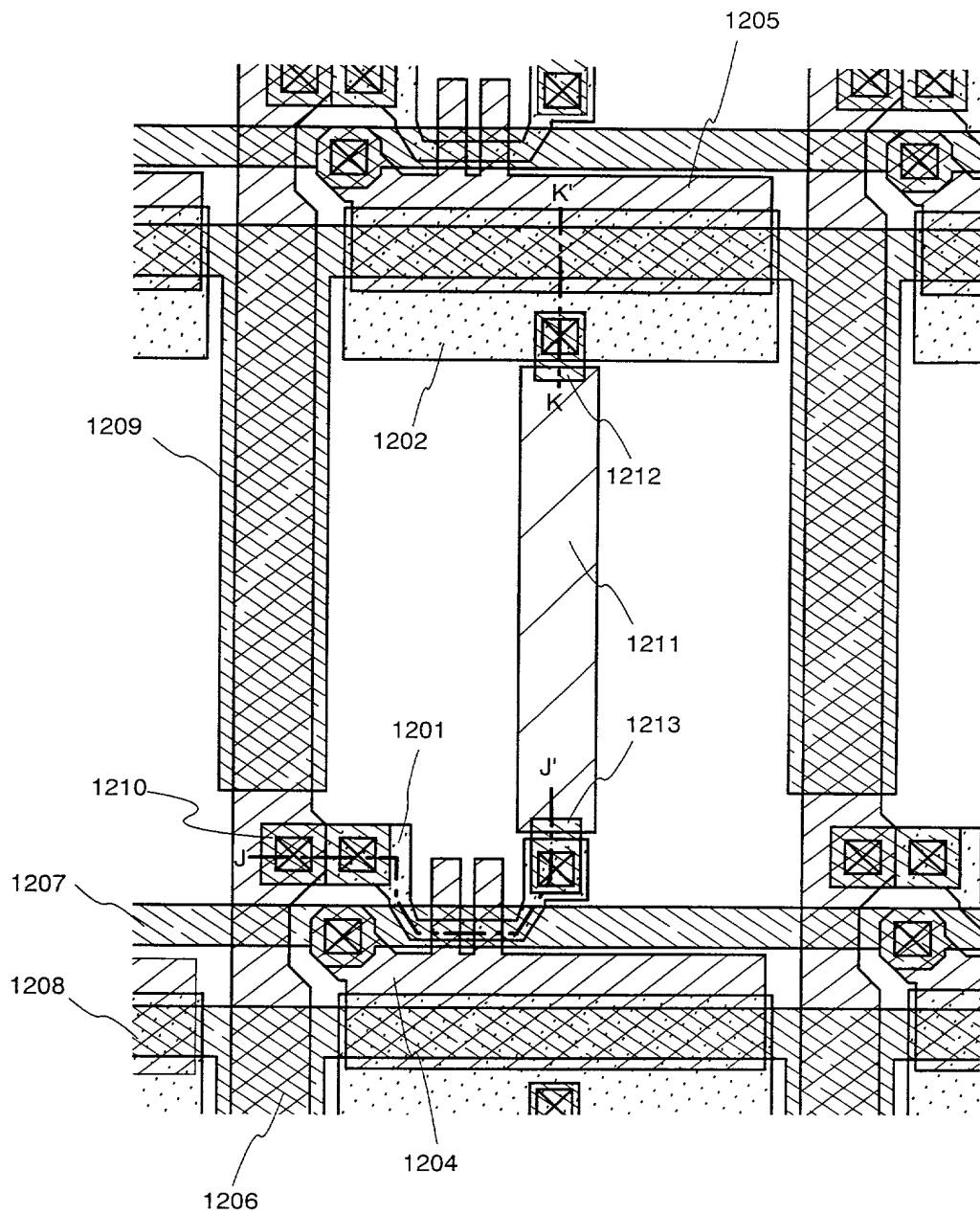


FIG. 18

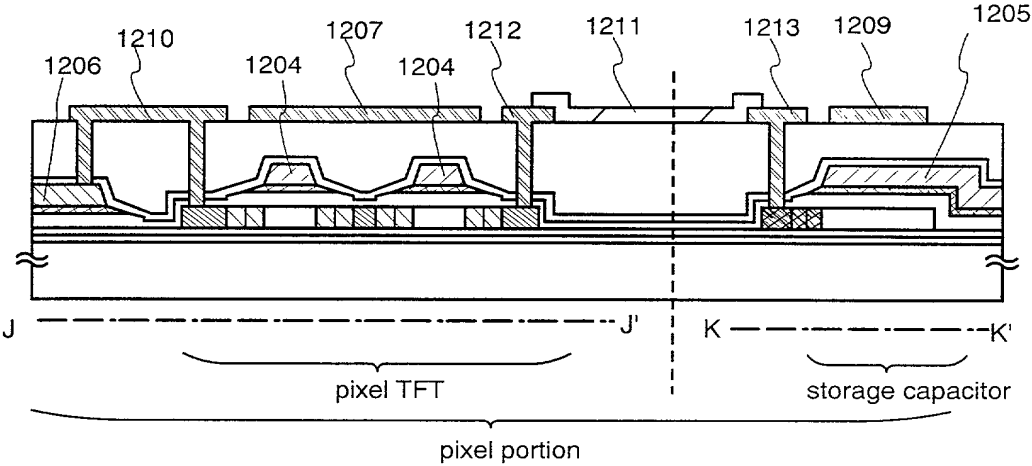
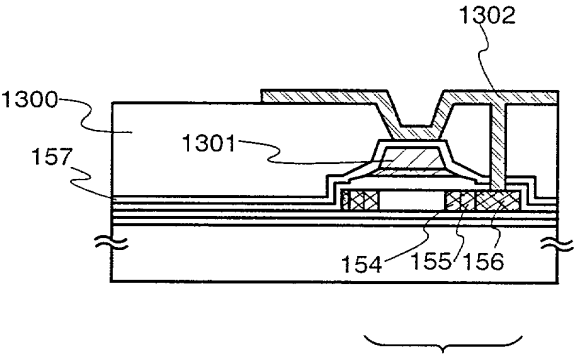


FIG. 19



405: storage capacitor

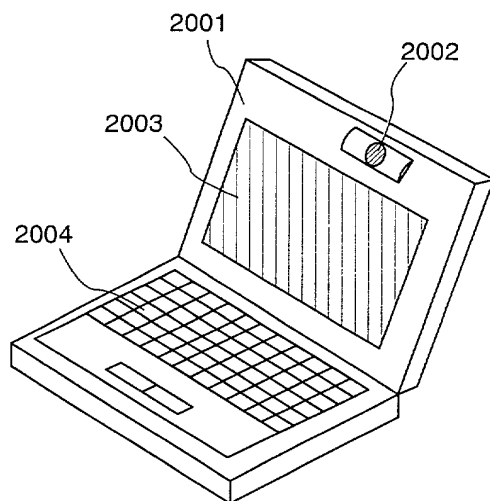


FIG. 20A

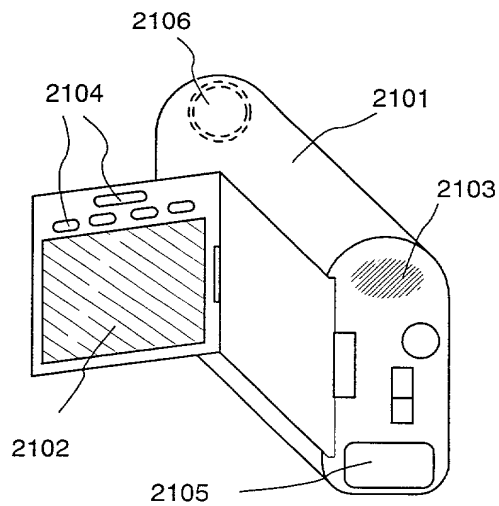


FIG. 20B

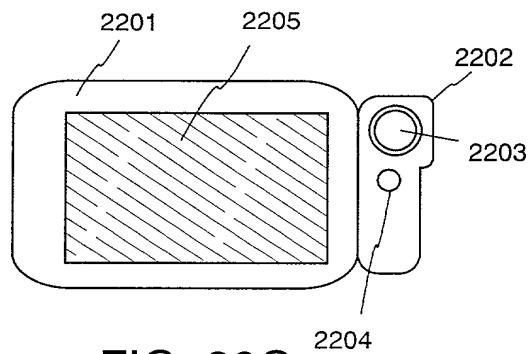


FIG. 20C

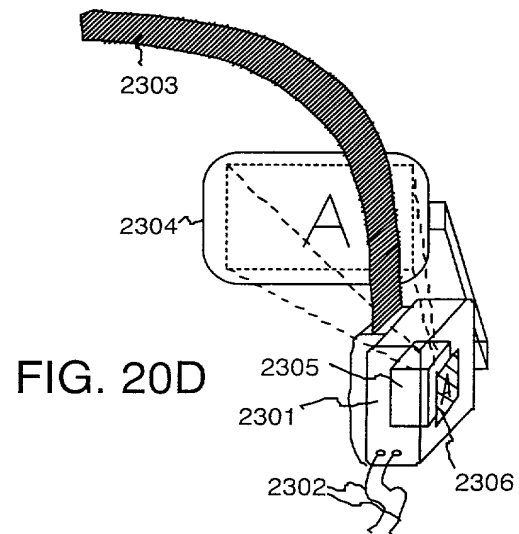


FIG. 20D

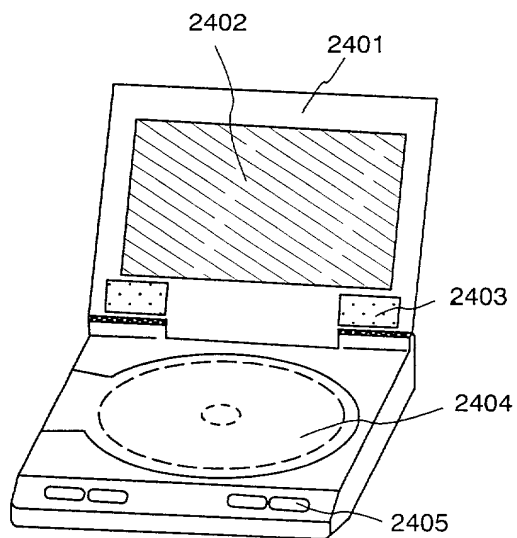


FIG. 20E

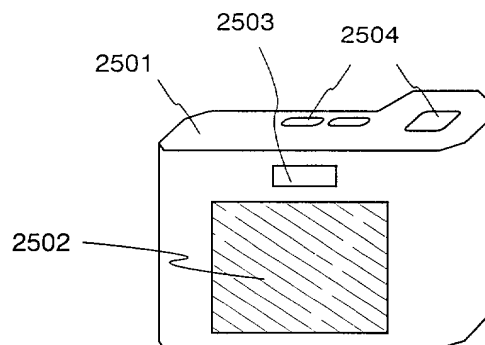


FIG. 20F

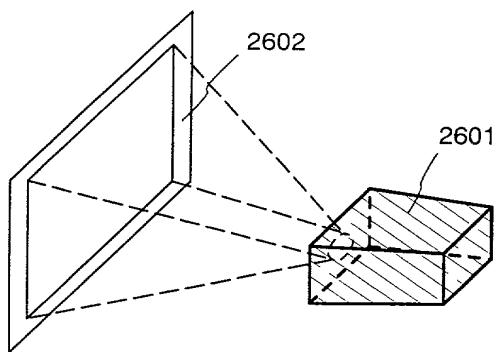


FIG. 21A

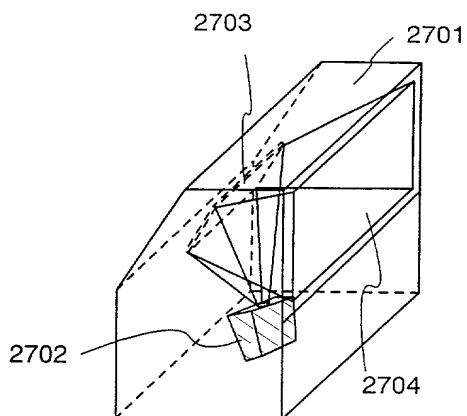


FIG. 21B

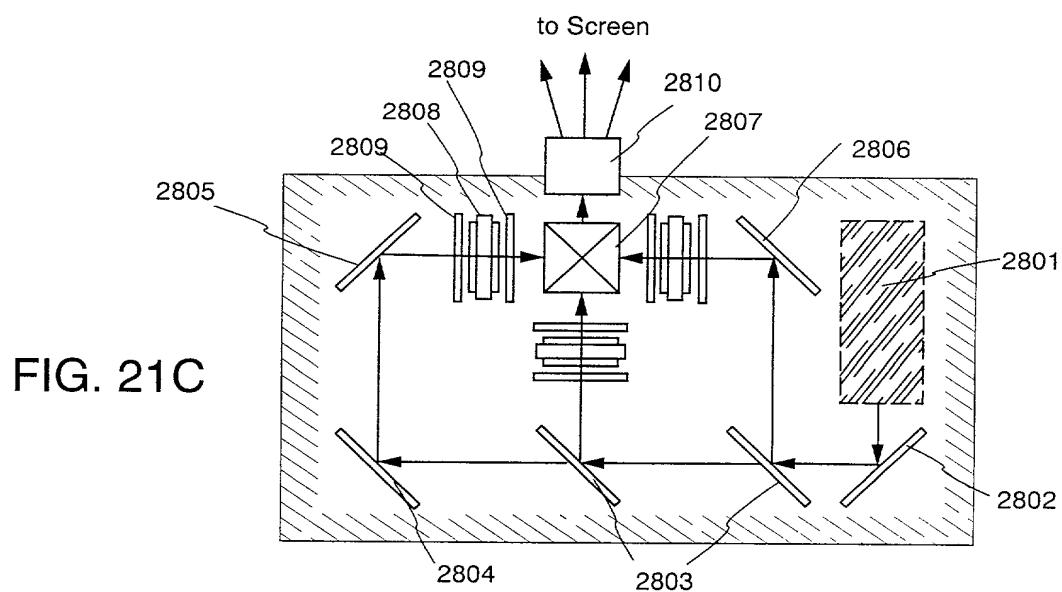


FIG. 21C

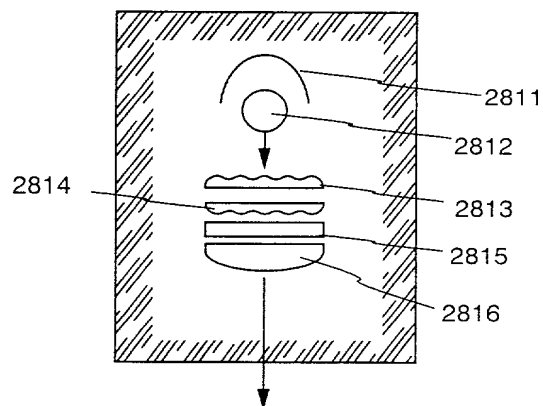


FIG. 21D

FIG. 22A

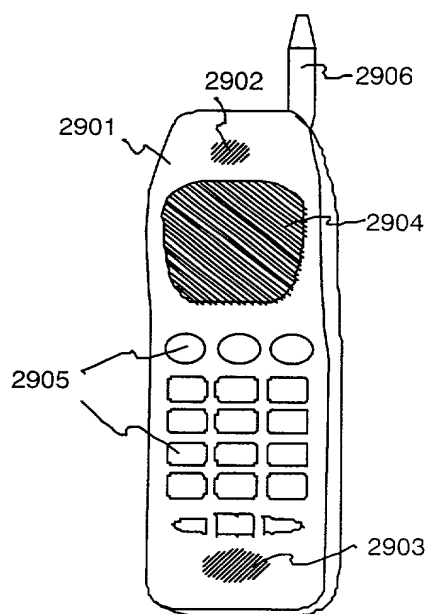


FIG. 22B

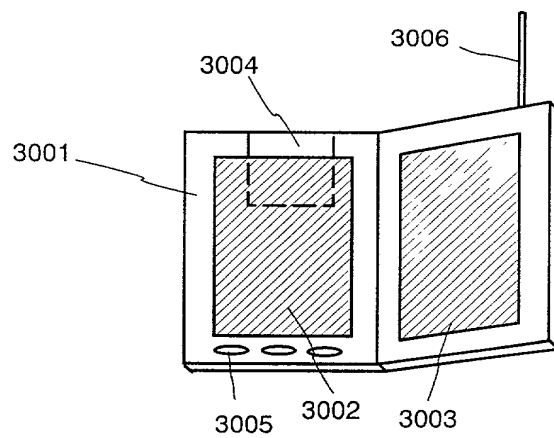


FIG. 22C

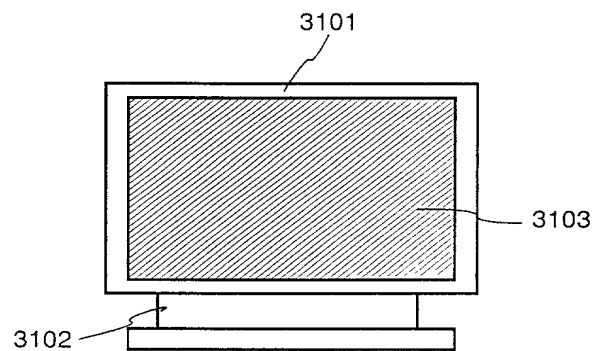


FIG. 23 prior art

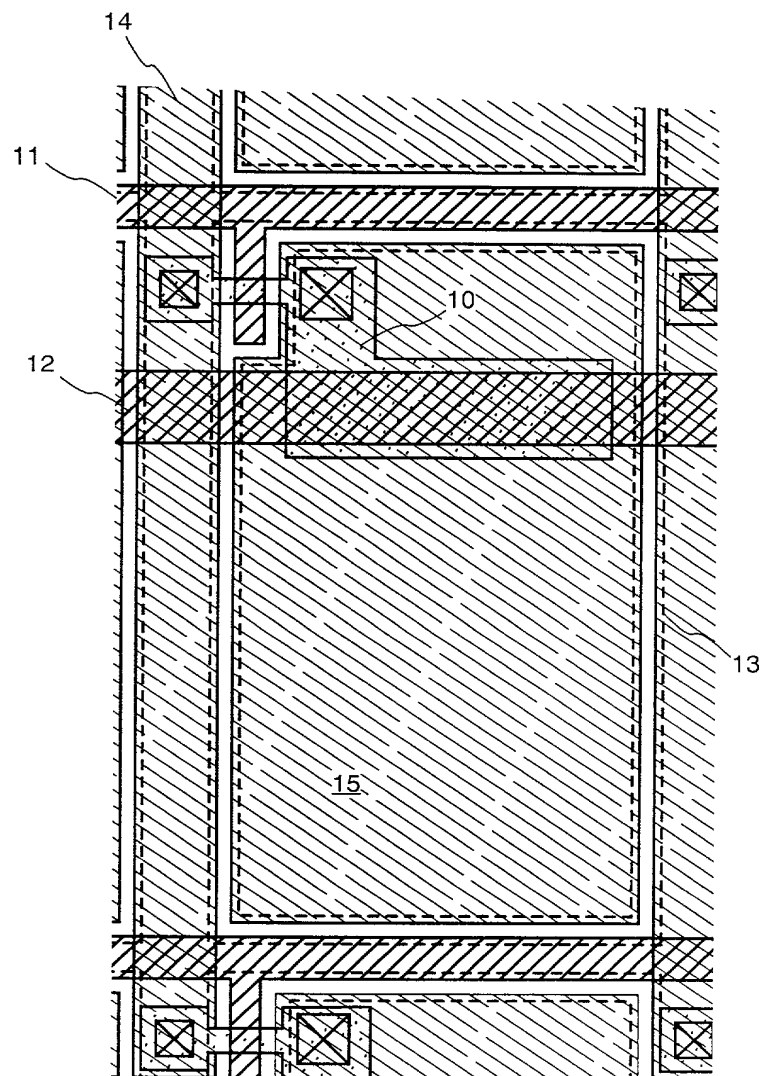


FIG. 24A

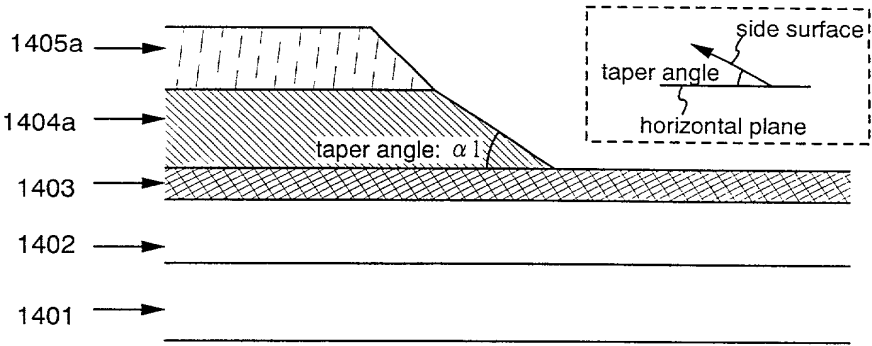


FIG. 24B

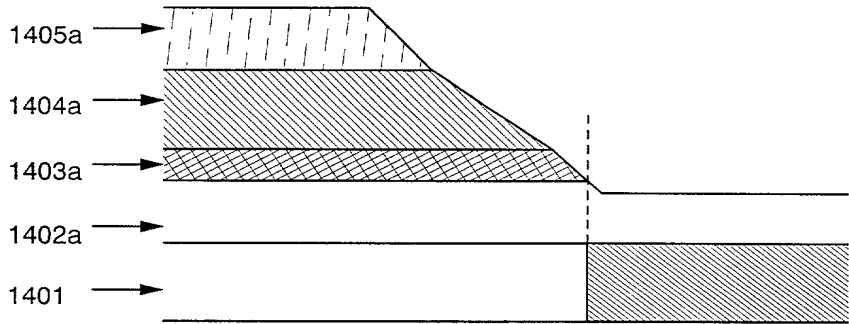


FIG. 24C

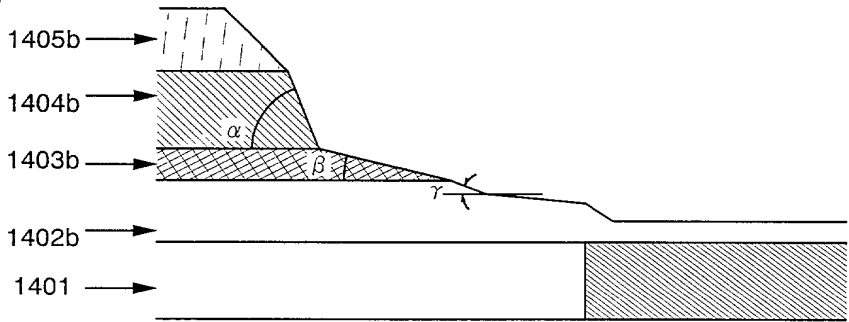


FIG. 24D

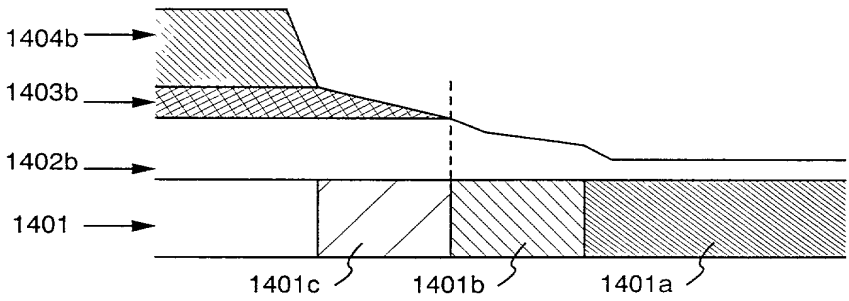




FIG. 25

